

Specifications

Drawing No.	USY1M-H1-17145-00	1 / 10
Issued Date.	Feb,20,2016	

Messrs: Digi-Key

Note: Part Number will be revised in case of specification change.

Product Type	Quartz Crystal
Series	CX2016DB
Frequency	38400kHz
Customer Part Number	-
Customer Specification Number	-
KYOCERA Part Number	CX2016DB38400C0WPLA2
Remarks	Pb-Free, RoHS Compliant, MSL 1

Customer Approval

Approval Signature	Approved Date	
	Department	
	Person in charge	

Seller

KYOCERA Crystal Device Corporation
(Sales Division)
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612-8501 Japan
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Manufacturer

KYOCERA Crystal Device Corporation
Crystal Units Division
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999-3701 Japan
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Design Department	Quality Assurance	Approved by	Checked by	Issued by
KYOCERA Crystal Device Corporation Crystal Unit Design Engineering Section Crystal Units Division	S. Itoh	T. Soda	A. Muraoka	T.Sudou Y.Nozaiki

Revision History

Rev. No.	Description of revise	Date	Approved by	Checked by	Issued by
00	First Edition	Feb,20,2016	T. Soda	A. Muraoka	T.Sudou Y.Nozaki

1. APPLICATION

The purpose of this document is applied to CX2016DB quartz crystal.

2. KYOCERA PART NUMBER

CX2016DB38400C0WPLA2

3. RATINGS

Items	SYMB.	Rating	Unit	Remarks
Operating Temperature range	Topr	-40 to +85	deg. C	
Storage Temperature range	Tstg	-40 to +85	deg. C	

4. CHARACTERISTICS

4-1 ELECTRICAL CHARACTERISTICS

Items	Electrical Specification					Test Condition	Remarks
	SYMB.	Min	Typ.	Max	Unit		
Mode of Vibration		Fundamental					
Nominal Frequency	F0		38.4		MHz		
Nominal Temperature	T _{NOM}		+25		deg. C		
Load Capacitance	CL		7.0		pF	IEC 60444-8 STD (Pi Circuit 41901A)	
Frequency tolerance	df/F	-20		+20	PPM	+25±3°C	
Frequency Stability	df/t					-40~+85deg.C	
Frequency drift after reflow						After 2times	
Frequency Aging Rate						25deg.C 5years	
Equivalent Series Resistance	ESR			25	Ohms	CL=SERIES	
Drive Level	Pd	10		200	μW		
Insulation Resistance	IR	500			M ohms	100V(DC)	

Measurement Condition

Frequency measurement

Measuring instrument : IEC PI-Network Test Fixture

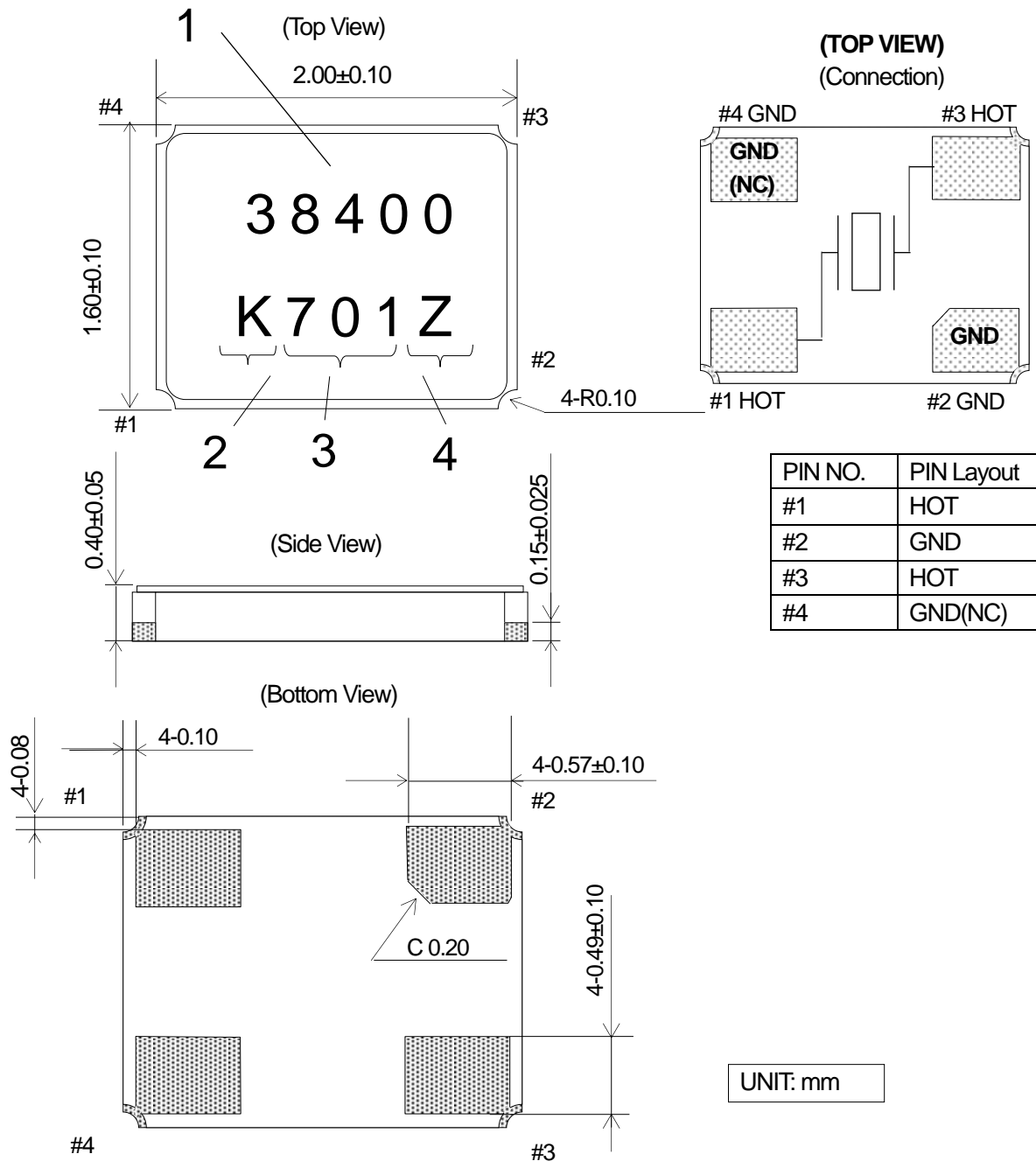
Equivalent series resistance (ESR) measurement

Measuring instrument : IEC PI-Network Test Fixture

Load Capacitance : Series

5. APPEARANCES, PHYSICAL DIMENSION

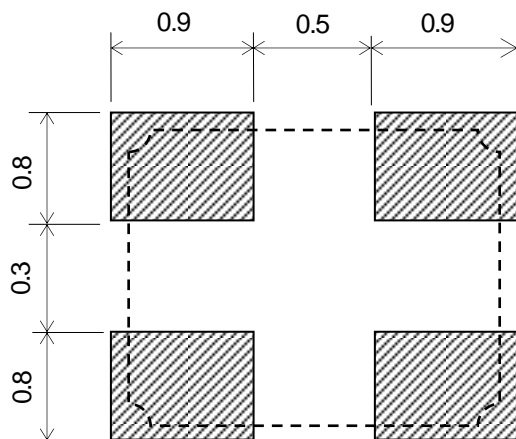
OUTLINE DIMENSION (not to scale)



MARKING

- | | | |
|---|------------------------|---|
| 1 | Nominal Frequency | First 5digit of the frequency is indicated. |
| 2 | Identification | [K] is to indicate 1Pin direction. |
| 3 | Date Code | Last 1 Digit of YEAR and WEEK (Ex) 2017,Jan,05 → 701 |
| 4 | Manufacturing Location | Y→Japan (Yamagata)
Z→Japan (Shiga Yohkaichi)
T→Thailand |

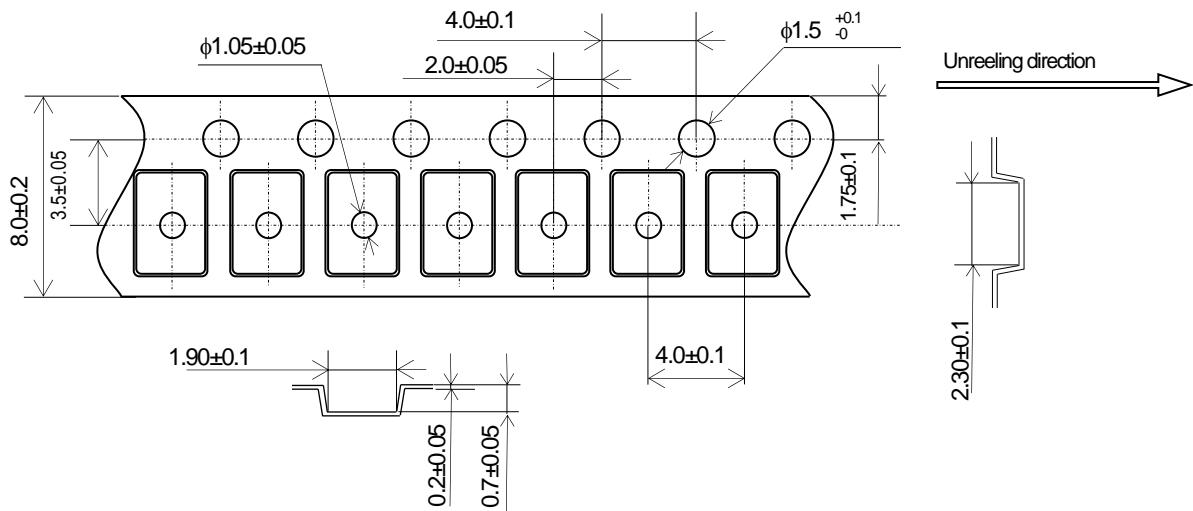
*The font of marking is for reference only.

6. RECOMMENDED LAND PATTERN (not to scale)

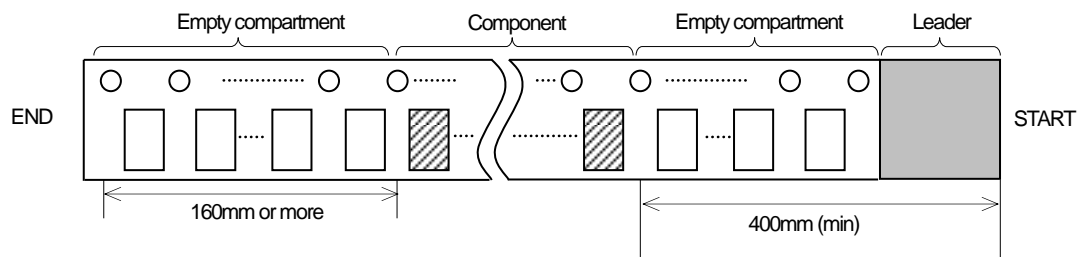
UNIT : mm

7. TAPING & REEL

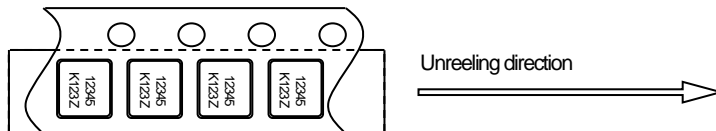
7-1. Dimensions



7-2. Leader and Carrier tape

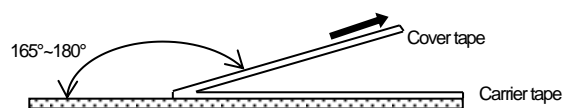


7-3. Direction (Orientation shall be checked from the top cover tape side)

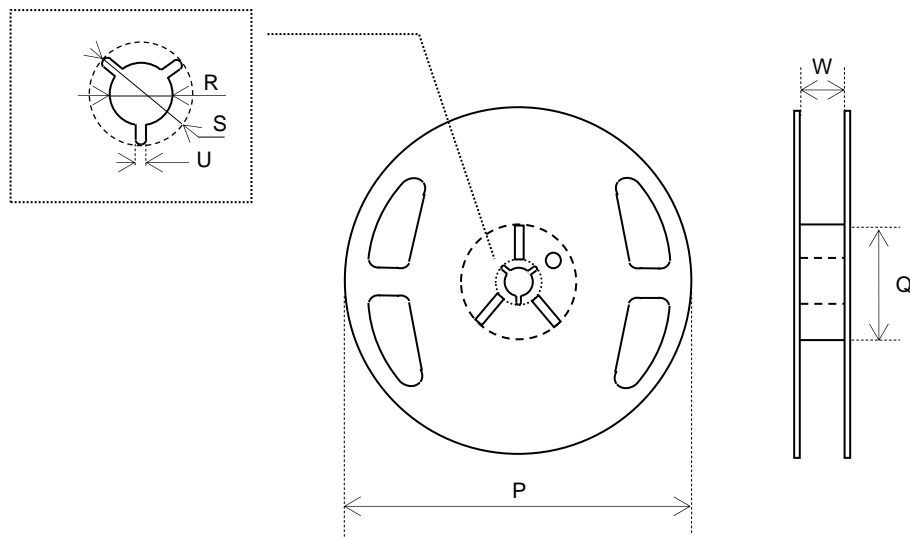


7-4. Specification

1. Material of the carrier tape is either polystyrene or A-PET (ESD).
2. Material of the cover tape is polyester (ESD).
3. The seal tape shall not cover the sprocket holes and not protrude from the carrier tape.
4. Tensile strength of carrier tape: 10N or more.
5. The R of the corner of each cavity is 0.2RMAX.
6. The alignment between centers of the cavity and sprocket hole shall be 0.05mm or less.
7. The orientation shall be checked from the top cover tape side as shown in 7-3.
8. Peeling force of cover tape: 0.1 to 1.0N.
9. The component will fall out naturally when cover tape is removed and set upside down.



7-5.Reel Specification



φ180 Reel (3,000 pcs Max.)

Symbol	P	Q	R
Dimension	φ180 +0/-3	φ60 +1/-0	φ13±0.2
Symbol	S	U	W
Dimension	φ21±0.8	2.0±0.5	9±1

(Unit: mm)

φ330 Reel (15,000 pcs Max.)

Symbol	P	Q	R
Dimension	φ330±2.0	φ100±1.0	φ13±0.2
Symbol	S	U	W
Dimension	φ21±0.8	2.0±0.5	9.4±1.0

(Unit: mm)

8. Enviromental requirements

After conducting the following tests, component needs to meet below conditions.

Frequency: Fluctuation within $\pm 10 \times 10^{-6}$

CI: Fluctuation within $\pm 20\%$ or 5Ω whichever is larger

- | | | | | | | | | | |
|-----------------------------|--|-----------|--|-----------|--|------------|--------------|-----------|-------------------------------|
| 8.1 Resistance to Shock | <p>Test condition</p> <p>3 times natural drop from 100cm onto hard wooden board.</p> | | | | | | | | |
| 8.2 Resistance to Vibration | <p>Test condition</p> <table border="0" style="margin-left: 40px;"> <tr> <td>frequency</td> <td>: 10 - 55 - 10 Hz</td> </tr> <tr> <td>Amplitude</td> <td>: 1.5mm</td> </tr> <tr> <td>Cycle time</td> <td>: 15 minutes</td> </tr> <tr> <td>Direction</td> <td>: X,Y,Z (3direction),2h each.</td> </tr> </table> | frequency | : 10 - 55 - 10 Hz | Amplitude | : 1.5mm | Cycle time | : 15 minutes | Direction | : X,Y,Z (3direction),2h each. |
| frequency | : 10 - 55 - 10 Hz | | | | | | | | |
| Amplitude | : 1.5mm | | | | | | | | |
| Cycle time | : 15 minutes | | | | | | | | |
| Direction | : X,Y,Z (3direction),2h each. | | | | | | | | |
| 8.3 Resistance to Heat | <p>Test condition</p> <p>The quartz crystal unit shall be stored at a temperature of $+85\pm 2^{\circ}\text{C}$ for 500h and subjected to room temperature for 1h before measurement.</p> | | | | | | | | |
| 8.4 Resistance to Cold | <p>Test condition</p> <p>The quartz crystal unit shall be stored at a temperature of $-40\pm 2^{\circ}\text{C}$ for 500h and subjected to room temperature for 1h before measurement.</p> | | | | | | | | |
| 8.5 Thermal Shock | <p>Test condition</p> <p>The quartz crystal unit shall be subjected to 500 temperature cycles shown in table below,Then it shall be subjected to room temperature for 1h before mesurement.</p> <table border="0" style="margin-left: 40px;"> <tr> <td>Cycle</td> <td>: $-40\pm 2^{\circ}\text{C}$ (30min.) \rightarrow $+25\pm 2^{\circ}\text{C}$ (5min.)</td> </tr> <tr> <td></td> <td>\rightarrow $+85\pm 2^{\circ}\text{C}$ (30min.) \rightarrow $+25\pm 2^{\circ}\text{C}$ (5min.)</td> </tr> </table> | Cycle | : $-40\pm 2^{\circ}\text{C}$ (30min.) \rightarrow $+25\pm 2^{\circ}\text{C}$ (5min.) | | \rightarrow $+85\pm 2^{\circ}\text{C}$ (30min.) \rightarrow $+25\pm 2^{\circ}\text{C}$ (5min.) | | | | |
| Cycle | : $-40\pm 2^{\circ}\text{C}$ (30min.) \rightarrow $+25\pm 2^{\circ}\text{C}$ (5min.) | | | | | | | | |
| | \rightarrow $+85\pm 2^{\circ}\text{C}$ (30min.) \rightarrow $+25\pm 2^{\circ}\text{C}$ (5min.) | | | | | | | | |

8.6 Resistance to Moisture

Test condition

The quartz crystal unit shall be stored at a temperature of $+60\pm 2^{\circ}\text{C}$ with relative humidity of 90% to 95% for 240 h. Then it shall be subjected to room temperature for 1h before measurement.

8.7 Soldering condition

1.) Type of solder

Material → lead free solder paste

Melting point → $+220\pm 5^{\circ}\text{C}$

2.) Reflow temp.profile

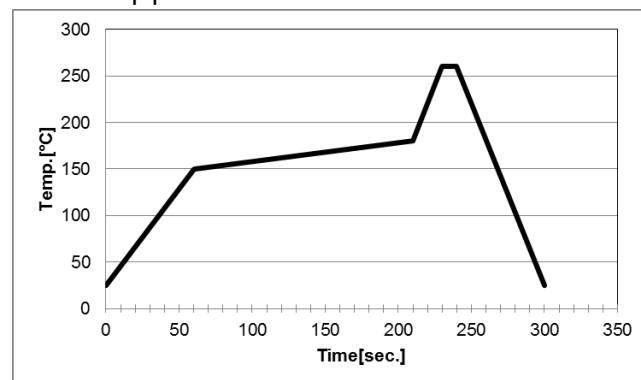
	Temp [$^{\circ}\text{C}$]	Time[sec]
Preheating	+150 to +180	150 (typ.)
Peak	$+260\pm 5$	10 (max.)
Total	-	300 (max.)

Frequency shift : $\pm 2\text{ppm}$

3.) Hand Soldering $+350^{\circ}\text{C}$ 3 sec max

4.) Reflow Times 2 times in below Reflow temp. profile

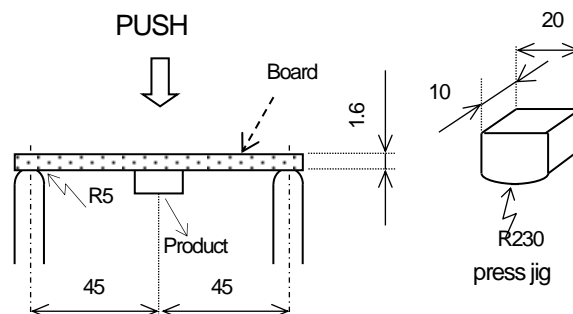
Reflow temp.profile



8.8 Bending Strength

Solder this product in center of the circuit board (40mm X 100mm), and add deflection of 3mm.

Test board : $t=1.6\text{mm}$



UNIT : mm

9. Cautions for use

(1) Soldering upon mounting

There is a possibility to influence product characteristics when Solder paste or conductive glue comes in contact with product lid or surface.

(2) When using mounting machine

Please minimize the shock when using mounting machine to avoid any excess stress to the product.

(3) Conformity of a circuit

We strongly recommend to make sure that Negative resistance (Gain) of IC is designed to be 3 times the ESR (Equivalent Series Resistance) of crystal unit.

10. Storage conditions

Please store product in below conditions, and use within 6 months.

Temperature +18 to +30°C, and Humidity of 20 to 70 % in the packaging condition.

11. Manufacturing location

Kyocera Crystal Device Corporation Yamagata Plant

Kyocera Crystal Device Corporation Shiga Yohkaichi Plant

Kyocera Crystal Device (Thailand) Co., Ltd

12. Quality Assurance

To be guaranteed by Kyocera Crystal Device Quality Assurance Division

13. Quality guarantee

In case when Kyocera Crystal Device Corporation rooted failure occurred within 1year after its delivery, substitute product will be arranged based on discussion. Quality guarantee of product after 1 year of its delivery is waived.

14. Others

In case of any questions or opinions regarding the Specification, please have it in written manner within 45 days after issued date.